

U.S. Patent Application Serial No. **09/851,946**  
Amendment dated September 9, 2003  
Reply to OA of **April 9, 2003**

**REMARKS**

Claim 1 is pending in this application. Claim 1 has been amended herein.

Support for the amendment to claim 1 may be found in the specification on page 6, lines 14-20, and page 7, lines 23-24.

**Claim 1 is rejected under 35 U.S.C. 102(b) as being anticipated by Libretti (U.S. Patent No. 5,187,431).**

Reconsideration of the rejection is respectfully requested in view of the amendment to claim 1, further clarifying the distinction between the present invention and Libretti.

The amendment to claim 1 clarifies that what was previously recited as “a plurality of substrates laminated separably” is “a plurality of laminated substrates” which have the characteristic that the “substrates can be separated one by one from the lowest layer” (that is, “peeled” as on page 6, line 15, of the present specification).

Libretti does illustrate probe card 3 as a multi-layered substrate in Figure 1. However, probe card 3 is a “printed circuit card”(see col. 3, line 67). Accordingly, it must incorporate wiring for connecting contacts 6 with probes 5, as may be seen by the relative locations of probes 5 and contacts 6 in Figure 1. Therefore, it is impossible to separate (peel) any layer of probe card 3 in Libretti.

Additionally, Applicants note that the probes drooping vertically in claim 1 do not correspond to stems 12a and 12b, even taken with contacts 6, as disclosed in the cited reference by Libretti.

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Particularly, stems 12a and 12b along with contacts 6 merely provide electrical connection between test card 10 and probe card 3, and these items have no possibility of wearing away through use.

Therefore, there is no suggestion or motivation in Libretti to correct for wear on the leading end of contact 6. Peeling off the lowest layer of probe card 3 would clearly serve no purpose in Libretti.

Applicants therefore assert that claim 1, as amended, is not anticipated by and, further, is non-obvious over Libretti.


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If, for any reason, it is felt that this application is not now in condition for allowance, the Examiner is requested to contact Applicants undersigned agent at the telephone number indicated below to arrange for an interview to expedite the disposition of this case.

In the event that this paper is not timely filed, Applicants respectfully petition for an appropriate extension of time. Please charge any fees for such an extension of time and any other fees which may be due with respect to this paper, to Deposit Account No. 01-2340.

Respectfully submitted,

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PATENT TRADEMARK OFFICE

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### IN THE CLAIMS

Please amend claim 1 as follows:

1. (Currently Amended): The vertical probe card having vertical probes for use in measurement of electric characteristics of the objects of measurement, comprising a main substrate forming conductive patterns, a plurality of probes drooping vertically from said main substrate, and a probe support provided at the back side of said main substrate from supporting said probes, wherein said probe support is disposed parallel to said main substrate, and has an upper guide plate and a lower guide plate for supporting the probes by passing through-holes opened in each, and said lower guide plate is composed of a plurality of laminated substrates ~~laminated separably, and said plurality of substrates can be separated one by one from the lowest layer to keep a necessary length of a leading end contact part of said probes in case of wear.~~